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Applicant Kunihiro MITSUTAKE et al.			
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U.S. PATENT DOCUMENTS			
Examiner Initial*		Document Number	Date
FOREIGN PATENT DOCUMENTS			
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OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages, Etc.)			
MCB	IKOTA, M. et al., "Discrimination of Clustered Defects on Wafers Using Statistical Methods", Proc. 1997 Second Int. Workshop Statistical Metrology, pp. 52-55.		
Examiner	Mary Catherine Brown		Date Considered 2/7/04
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